

**Search Notes**

Application/Control No.

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Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

KOBAYASHI ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15	4/14/2006	HN
358	1.16	4/14/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM; TDB) (see search report printout)	4/14/2006	HN